

Problem We would like to use a pn junction as a thermal sensor.

To do so, we keep the junction current constant and measure the junction voltage as a function of temperature.

Use the diode equation



$$|I_d \approx I_s e^{\frac{V_d}{V_T}}| \quad \text{where } I_s = A \cdot q \cdot n_{i0}^2 \frac{D_n}{L_n N_A}$$

to find an expression for the expected change of the diode voltage V_d

Solution

1. We assume that $\frac{D_n}{L_n}$ approximately remains constant over the temperature range of interest.

$$\therefore \left| \frac{dI_s}{dT} \approx \frac{dn_{i0}^2}{dT} \right|$$

2. From $n_{i0} = N_c(T) e^{-\frac{E_c - E_{Fi}}{kT}} = N_v(T) e^{-\frac{E_{Fi} - E_v}{kT}}$

we obtain

$$n_{i0}^2(T) = N_c(T) \cdot N_v(T) e^{-\frac{E_c - E_v}{kT}}$$

where

$$N_c(T) \cdot N_v(T) = 4 \left(\frac{2\pi kT}{h^2} \right)^3 (m_n^* m_p^*)^{3/2}$$

We can thus write

$$I_S(T) = I_{S0} \left(\frac{T}{T_0} \right)^3 e^{\frac{E_G}{kT_0} \left(1 - \frac{T_0}{T} \right)}$$

The derivative of I_S w.r.t. T is

$$\frac{dI_S(T)}{dT} = \underbrace{I_{S0} \left(\frac{T}{T_0} \right)^3 e^{\frac{E_G}{kT_0} \left(1 - \frac{T_0}{T} \right)}}_{I_S(T)} \left[\frac{3}{T} + \frac{E_G}{kT^2} \right]$$

$$\therefore \left\| \frac{dI_S(T)}{dT} = \frac{I_S(T)}{T} \left[3 + \frac{E_G}{kT} \right] \right\| \quad (1)$$

Note: $\frac{E_G}{kT} = \frac{V_G}{V_T}$ where $V_G = \frac{E_G}{q}$ Bandgap voltage

3. Solving the original diode equation for the diode voltage yields

$$|V_d \approx V_T \ln\left(\frac{I_d}{I_S}\right)| \quad \text{where } I_d = I_{d0}$$

$$\left\| \frac{dV_d(T)}{dT} = \frac{dV_T}{dT} \ln\left(\frac{I_{d0}}{I_S}\right) - V_T \frac{1}{I_S} \frac{dI_S}{dT} \right\| \quad (2)$$

4. Finally, inserting (1) into (2) yields

$$\frac{dV_d(T)}{dT} = \frac{V_T}{T} \ln\left(\frac{I_{d0}}{I_S}\right) - \frac{V_T}{T} \left[3 + \frac{V_G}{V_T} \right]$$

or

$$\left\| \frac{dV_d(T)}{dT} = \frac{1}{T} [V_d - 3V_T - V_G] \right\| \quad (3)$$

Numerical Solutions

Find the values for $\frac{dV_d(T)}{dT}$ between 300k and 400k if we know that $V_d @ 300k$ is 0.7V

| T [K] | dV_d/dT [mV/K] | V_d [mV] |
|------------|---------------------|---------------|
| 300 | -1.659 | 700.0 |
| 320 | -1.675 | 666.8 |
| 340 | -1.690 | 633.3 |
| 360 | -1.704 | 599.5 |
| 380 | -1.718 | 565.4 |
| 400 | -1.731 | 531.0 |

$$V_{G_{Si}} = 1.12V$$

Note: The numerical values depend crucially on the initial diode voltage

second order approximation for diode voltage: (300k - 400k)

$$\| V_d(T) \cong V_{d0} + \Delta T k_1 + \Delta T^2 k_2 \|$$

where

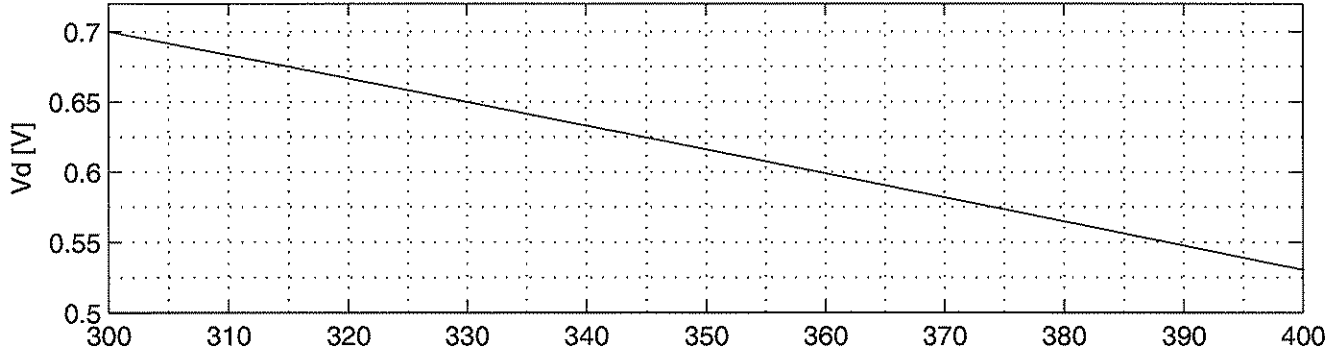
$$\begin{array}{|l} k_1 \cong -1.697 \text{ mV/K} \\ k_2 \cong -0.37 \mu\text{V/K}^2 \end{array}$$

Values are referenced to 350K

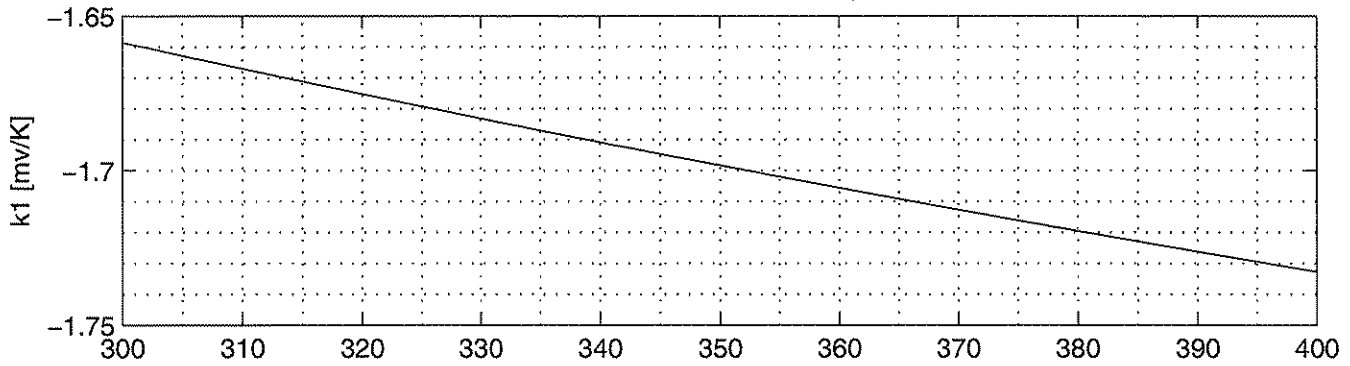
Notes If one were to compensate for the linear deviation of the diode voltage (e.g. in a voltage reference circuit), one would end up with a quadratic (parabolic) error, i.e., $\Delta V_d = k_2 \cdot \Delta T^2$

V1-P4

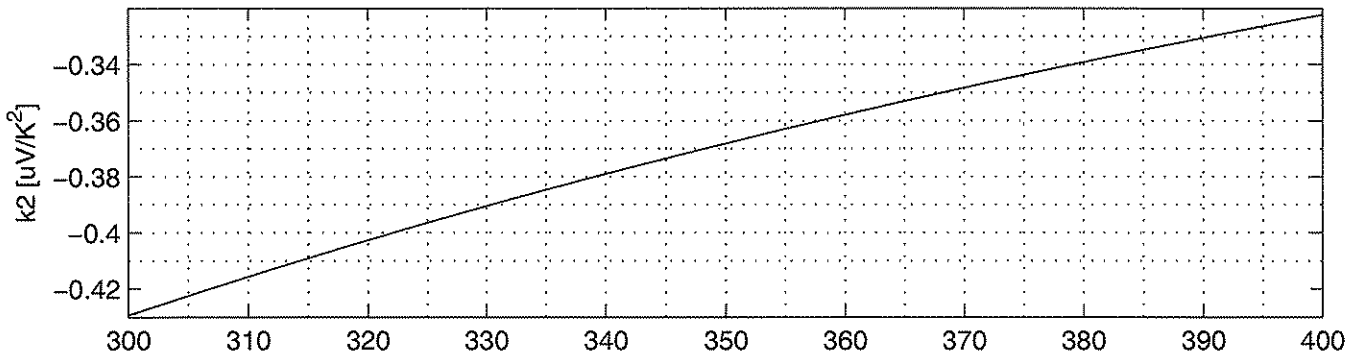
Diode Voltage versus Temperature



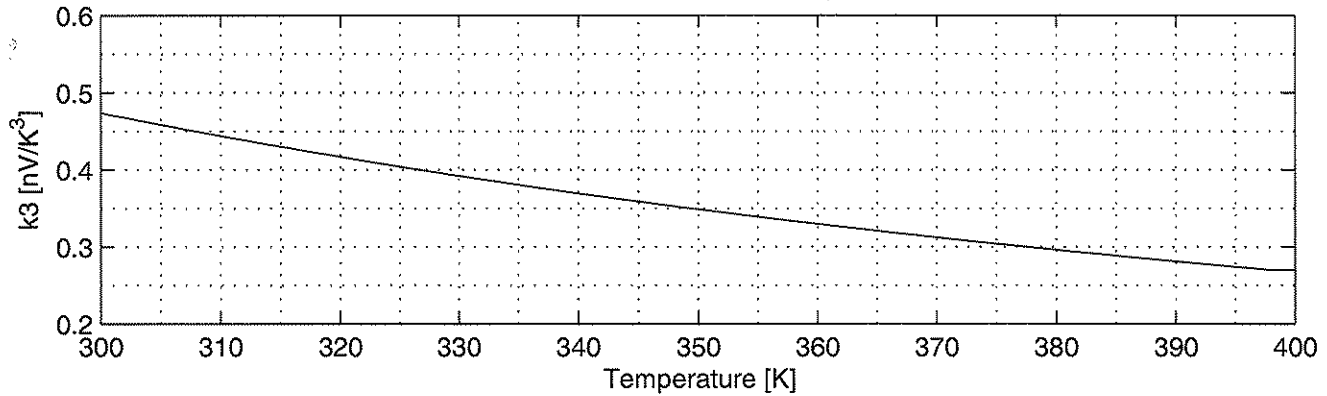
Linear Coefficient versus Temperature



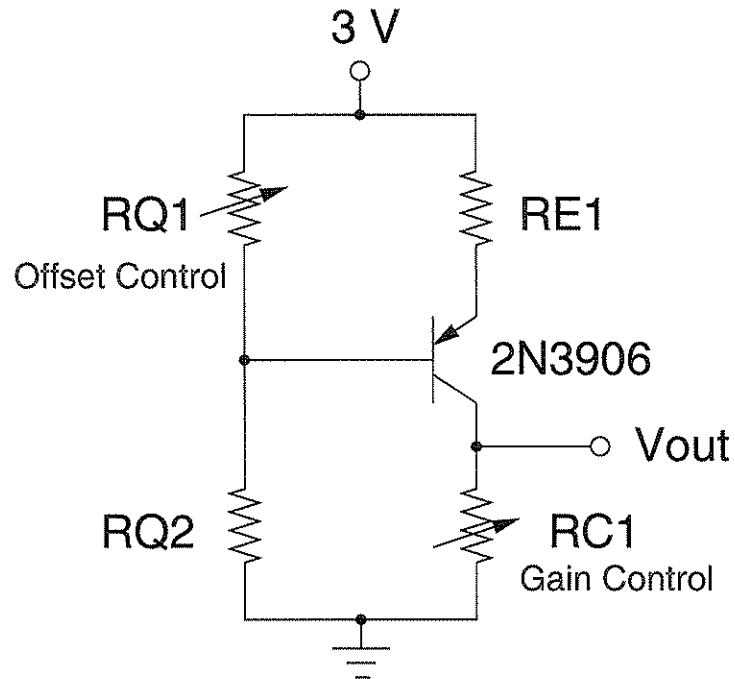
Quadratic Coefficient versus Temperature



Cubic Coefficient versus Temperature



Single Transistor Thermal Sensor



Component Power Dissipation

| | | | |
|------------|--------------|-----------|----------------------|
| RQ1 = 82k | 8.1 μ W | RE1 = 15k | 8.3 μ W (100 C) |
| | | | 2.0 μ W (0 C) |
| RQ2 = 220k | 21.8 μ W | RC1 = 90k | 49.8 μ W (100 C) |
| | | | 12.2 μ W (0 C) |
| | | 2N3906 | 12.4 μ W (100 C) |
| | | | 20.7 μ W (0 C) |

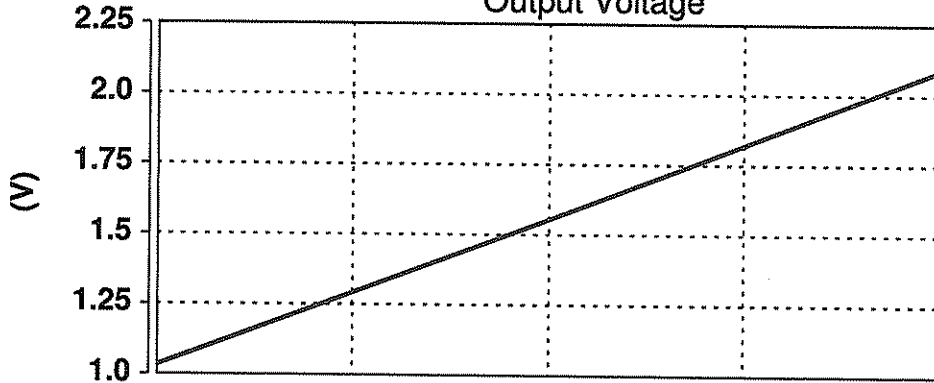
$$V_{out} = k_1 \Delta T + k_2 \Delta T^2$$

@ T=50 C $k_1 = 10.67 \text{ mV/K}$ $k_2 = 2.6 \text{ } \mu\text{V/K}^2$

Thermal Sensor Version 1

Output Voltage

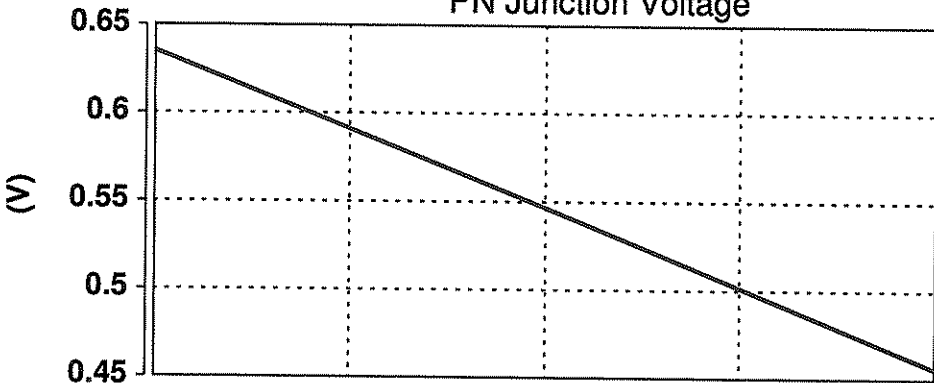
(V) : Temperature(deg)



v(out)

PN Junction Voltage

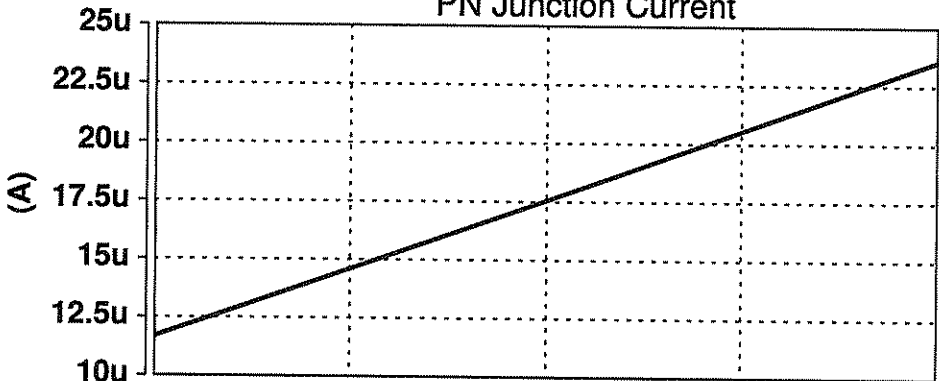
(V) : Temperature(deg)



v(ve,vb)

PN Junction Current

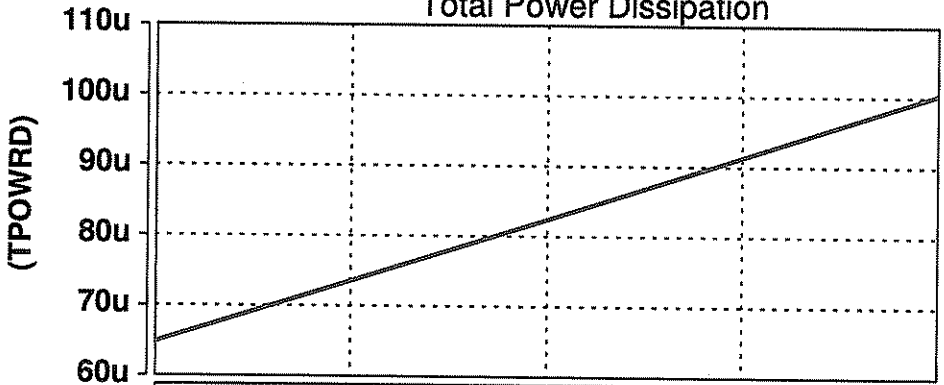
(A) : Temperature(deg)



i(re1)

Total Power Dissipation

(TPOWRD) : Temperature(deg)



1TPOWRD(power)

Temperature(deg)